

WHAT IS CLAIMED IS:

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1. A contactor used for testing an integrated circuit electronic component provided with a plurality of electrodes, said contactor comprising:

10 an insulating base material provided with holes formed at positions corresponding to said electrodes;

15 a first conductive layer having contacts which are plastically deformed portions of said first conductive layer, said contacts being provided at positions corresponding to said electrodes for enabling an electrical connection to said electronic component and being protruded from said insulating base material; and

20 reinforcement members provided on said contacts on a first surface of said contacts, said first surface being facing towards said holes.

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2. The contactor as claimed in claim 1, wherein said contacts are recessed into said insulating base material.

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3. The contactor as claimed in claim 1, wherein said contact has a top rim part surrounding an opening at the top of said contact.

4. The contactor as claimed in claim 1,
wherein said contact has an irregular top part.

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10 5. The contactor as claimed in claim 1,
wherein said insulating base material has reduced
thickness at positions corresponding to said contacts.

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6. The contactor as claimed in claim 1 wherein
said reinforcement members are leveled with said
insulating base material.

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25 7. The contactor as claimed in claim 1 wherein
said reinforcement members are protruded from said
insulating base material.

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8. The contactor as claimed in claim 1 wherein
said reinforcement members are plated members.

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9. The contactor as claimed in claim 1 further
comprising a non-conductive layer covering said first

conductive layer except for positions corresponding to said contacts.

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10. The contactor as claimed in claim 1 further comprising a further plated member provided on said first conductive layer which may be in direct contact with said electrode.

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11. The contactor as claimed in claim 1 further comprising a second conductive layer provided on said insulating base material on an opposite side to said first conductive layer, the reinforcement member being provided so as to enable an electrical connection between said first conductive layer and said second conductive layer.

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12. A method of manufacturing a contactor used for testing an integrated circuit electronic component provided with a plurality of electrodes, said method comprising the steps of:

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a) preparing a wiring substrate having an insulating base material and a first conductive layer; and

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b) forming contacts by mechanically pressing said wiring substrate such that said first conductive layer is plastically deformed at positions corresponding to said electrodes.

13. The method as claimed in claim 12, wherein
5 said step a) comprises the step of forming holes in
said insulating base material at positions
corresponding to said electrodes,
and wherein said method further comprises
the step of:
10 c) providing reinforcement members on said
contacts a first surface of said contacts, said first
surface being facing towards said holes.

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14. A device for testing an integrated
circuit electronic component provided with a plurality
of electrodes using a contactor comprising:
20 an insulating base material provided with
holes formed at positions corresponding to said
electrodes;
a first conductive layer having contacts
which are plastically deformed portions of said first
25 conductive layer, said contacts being provided at
positions corresponding to said electrodes for
enabling an electrical connection to said electronic
component and being protruded from said insulating
base material; and
30 reinforcement members provided on said
contacts on a first surface of said contacts, said first
surface being facing towards said holes.

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15. The device as claimed in claim 14, wherein

said contactor is positioned such that said contacts are protruded from said insulating base material towards said electronic component.

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16. The device as claimed in claim 14, wherein
said contactor is positioned such that said contacts
10 are recessed into said insulating base material away
from said electronic component.

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17. The device as claimed in claim 14, wherein
said contactor is positioned such that said first
conductive layer is provided at a side opposite to said
electronic component and said contacts are protruded
20 from said insulating base material away from said
electronic component.

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18. A method of testing an integrated circuit
electronic component provided with a plurality of
electrodes using a contactor comprising:

30 an insulating base material provided with
holes formed at positions corresponding to said
electrodes;

35 a first conductive layer having contacts
which are plastically deformed portions of said first
conductive layer, said contacts being provided at
positions corresponding to said electrodes for
enabling an electrical connection to said electronic
component and being protruded from said insulating

base material; and

reinforcement members provided on said contacts on a first surface of said contacts, said first surface being facing towards said holes, said method

5 comprising the step of:

a) electrically connecting said contacts of said contactor and said electrodes of said electronic component.

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19. The device as claimed in claim 18, wherein said contactor is positioned such that said contacts

15 are protruded from said insulating base material towards said electronic component.

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20. The device as claimed in claim 18, wherein said contactor is positioned such that said contacts are recessed into said insulating base material away from said electronic component.